SN54ACT373 . . . J OR W PACKAGE

SCAS544B - OCTOBER 1995 - REVISED MAY 1996

Inputs Are TTL-Voltage Compatible

● *EPIC*[™] (Enhanced-Performance Implanted CMOS) 1-μm Process

 Package Options Include Plastic Small-Outline (DW) Shrink Small-Outline (DB), and Thin Shrink Small-Outline (PW) Packages, Ceramic Chip Carriers (FK) and Flatpacks (W), and Standard Plastic (N) and Ceramic (J) DIPs

description

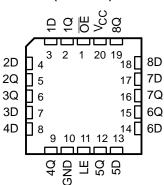
These 8-bit latches feature 3-state outputs designed specifically for driving highly capacitive or relatively low-impedance loads. The devices are particularly suitable for implementing buffer registers, I/O ports, bidirectional bus drivers, and working registers.

The eight latches are D-type transparent latches. When the latch-enable (LE) input is high, the Q outputs follow the data (D) inputs. When LE is taken low, the Q outputs are latched at the logic levels set up at the D inputs.

A buffered output-enable (\overline{OE}) input can be used to place the eight outputs in either a normal logic state (high or low logic levels) or the highimpedance state. In the high-impedance state, the outputs neither load nor drive the bus lines significantly. The high-impedance state and increased drive provide the capability to drive bus lines in bus-organized systems without need for interface or pullup components.

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SN74ACT373 [DB, DW,	N, O	R PW PACKAGE								
		EW)									
	-										
<u> </u>	\Box										
OEL	1	20	V _{CC}								
1Q 🛛	2	19	8Q								
1D 🛛	3	18	8D								
2D 🛛	4	17	7D								
2Q [5	16	7Q								
3Q [6	15	6Q								
3D [7	14	6D								
4D 🛛	8	13	5D								
4Q [9	12	5Q								
GND [10	11	LE								

SN54ACT373 ... FK PACKAGE (TOP VIEW)



OE does not affect the internal operations of the latches. Old data can be retained or new data can be entered while the outputs are in the high-impedance state.

The SN54ACT373 is characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ACT373 is characterized for operation from -40° C to 85° C.

FUNCTION TABLE (each latch)									
	INPUTS		OUTPUT						
OE	LE	D	Q						
L	Н	Н	Н						
L	н	L	L						
L	L	Х	Q ₀						
н	Х	Х	z						



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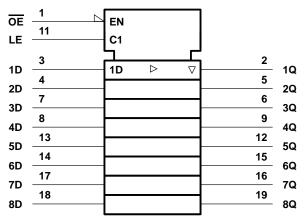
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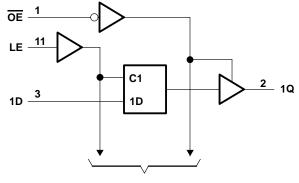


SCAS544B - OCTOBER 1995 - REVISED MAY 1996

logic symbol[†]



logic diagram (positive logic)



To Seven Other Channels

[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[‡]

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, V _I (see Note 1)	–0.5 V to V _{CC} + 0.5 V
Output voltage range, V _O (see Note 1)	–0.5 V to V _{CC} + 0.5 V
Input clamp current, I_{IK} ($V_I < 0$ or $V_I > V_{CC}$)	±20 mA
Output clamp current, I_{OK} ($V_O < 0$ or $V_O > V_{CC}$)	±20 mA
Continuous output current, $I_O (V_O = 0 \text{ to } V_{CC})$	
Continuous current through V _{CC} or GND	±200 mA
Maximum power dissipation at $T_A = 55^{\circ}C$ (in still air) (see Note 2)): DB package 0.6 W
	DW package 1.6 W
	N package 1.3 W
	PW package0.7 W
Storage temperature range, T _{stg}	–65°C to 150°C

‡ Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
 - The maximum package power dissipation is calculated using a junction temperature of 150°C and a board trace length of 750 mils, except for the N package, which has a trace length of zero.



SCAS544B - OCTOBER 1995 - REVISED MAY 1996

recommended operating conditions (see Note 3)

		SN54ACT373		373 SN74ACT373		UNIT
		MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2		2		V
VIL	Low-level input voltage		0.8		0.8	V
VI	Input voltage	0	VCC	0	VCC	V
Vo	Output voltage	0	Vcc	0	VCC	V
ЮН	High-level output current		-24		-24	mA
IOL	Low-level output current		24		24	mA
$\Delta t / \Delta v$	Input transition rise or fall rate	0	8	0	8	ns/V
Т _А	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: Unused inputs must be held high or low to prevent them from floating.

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	Vee	Г	Γ _A = 25°0	C	SN54A	CT373	SN74ACT373		UNIT			
PARAMETER	TEST CONDITIONS	Vcc	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT			
		4.5 V	4.4	4.49		4.4		4.4		V			
	I _{OH} = -50 μA	5.5 V	5.4	5.49		5.4		5.4					
Vari	lou - 21 mA	4.5 V	3.86			3.7		3.76					
VOH	I _{OH} = –24 mA	5.5 V	4.86			4.7		4.76		v			
	I _{OH} = -50 mA†	5.5 V				3.85							
	I _{OH} = -75 mA†	5.5 V						3.85					
	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V			
	IOL = 50 μA	5.5 V			0.1		0.1		0.1				
Ve		4.5 V			0.36		0.44		0.44				
VOL	I _{OL} = 24 mA	5.5 V			0.36		0.44		0.44				
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V					1.65						
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V							1.65				
I _{OZ}	$V_{O} = V_{CC}$ or GND	5.5 V			±0.25		±5		±2.5	μA			
Ц	$V_{I} = V_{CC}$ or GND	5.5 V			±0.1		±1		±1	μA			
ICC	$V_{I} = V_{CC} \text{ or } GND, \qquad I_{O} = 0$	5.5 V			4		80		40	μA			
ΔI_{CC}^{\ddagger}	One input at 3.4 V, One inputs at GND or V _{CC}	5.5 V			0.6		1.5		1.5	μA			
Ci	$V_I = V_{CC}$ or GND	5 V		4.5						pF			

[†] Not more than one output should be tested at a time, and the duration of the test should not exceed 2 ms.

[‡]This is the increase in supply current for each input that is at one of the specified TTL voltage levels rather than 0 V or V_{CC}.



SN54ACT373, SN74ACT373 **OCTAL D-TYPE TRANSPARENT LATCHES** WITH 3-STATE OUTPUTS SCAS544B - OCTOBER 1995 - REVISED MAY 1996

timing requirements over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

		T _A = 25°C		SN54ACT373		SN74ACT373		UNIT
		MIN	MAX	MIN	MAX	MIN	MAX	UNIT
tw	Pulse duration, LE high	7		8.5		8		ns
t _{su}	Setup time, data before LE \downarrow	7		8.5		8		ns
t _h	Hold time, data after LE \downarrow	0		1		1		ns

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

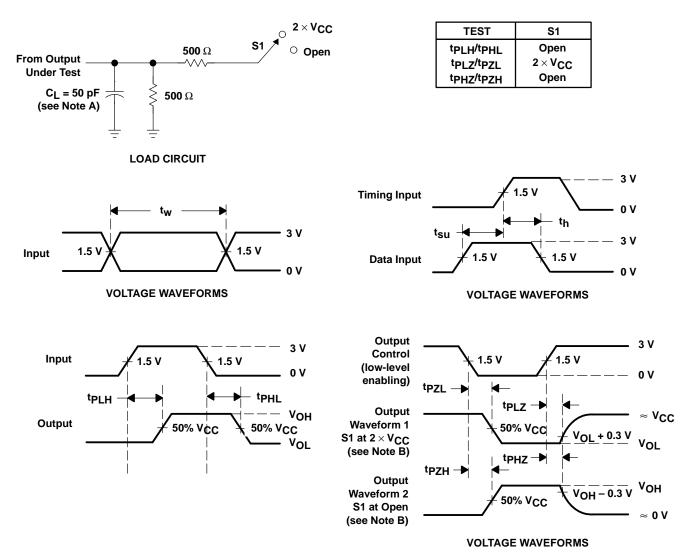
PARAMETER	то	то	T _A = 25°C			SN54ACT373		SN74ACT373		UNIT
FARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
^t PLH	D	Q	2.5	8.5	10	1.5	12.5	1.5	11.5	-
^t PHL	U	Q	2	8	10	1.5	12.5	1.5	11.5	ns
^t PLH	LE	Q	2.5	8.5	11	1.5	12.5	2	11.5	
^t PHL	LC		2	8	10	1.5	11.5	1.5	11.5	ns
^t PZH	OE	Q	2	8	9.5	1.5	11.5	1.5	10.5	
^t PZL	OE	Q	2	7.5	9	1.5	11	1.5	10.5	ns
^t PHZ	ŌĒ	Q	2.5	9	11	1.5	14	2.5	12.5	00
^t PLZ	UE UE	Ŷ	1.5	7.5	8.5	1.5	11	1	10	ns

operating characteristics, V_{CC} = 5 V, T_A = 25°C

PARAMETER		TEST CON	TYP	UNIT	
C _{pd}	Power dissipation capacitance	C _L = 50 pF,	f = 1 MHz	40	pF



SCAS544B - OCTOBER 1995 - REVISED MAY 1996



PARAMETER MEASUREMENT INFORMATION

NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, Z_O = 50 Ω , t_r \leq 2.5 ns, t_f \leq 2.5 ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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